

FDMC15N06 N-Channel MOSFET 55V, 15A, 0.090Ω

Features

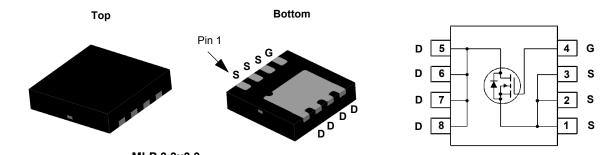
- $R_{DS(on)} = 0.075\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 15A$
- 100% Avalanche Tested
- RoHS Compliant



July 2009

Description

These N-Channel power MOSFETs are manufactured using the innovative UltraFET process. This advanced process technology achieves the lowest possible on-resistance per silicon area, resulting in outstanding performance. This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, lowvoltage bus switches, and power management in portable and battery-operated products.



MLP 3.3x3.3

MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units
V _{DSS}	Drain to Source Voltage		55	V	
V _{GSS}	Gate to Source Voltage			±20	V
ID		-Continuous (T _C = 25 ^o C)		15	^
	Drain Current	-Continuous (T _C = 100 ^o C)		9	Α
		- Continuous (T _A = 25 ^o C)	(Note 1a)	2.4	A
I _{DM}	Drain Current	- Pulsed	(Note 2)	60	А
E _{AS}	Single Pulsed Avalanche Energy (Note 3)		(Note 3)	36	mJ
I _{AR}	Avalanche Current		15	A	
E _{AR}	Repetitive Avalanche Energy		3.5	mJ	
P _D	Power Dissipation	(T _C = 25°C)		35	W
		$(T_{C} = 25^{\circ}C)$ $(T_{A} = 25^{\circ}C)$		2.3	W
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

Thermal Characteristics

Symbol	Parameter	Ratings	Units	
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	3.5	°C/W	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	°C/VV	

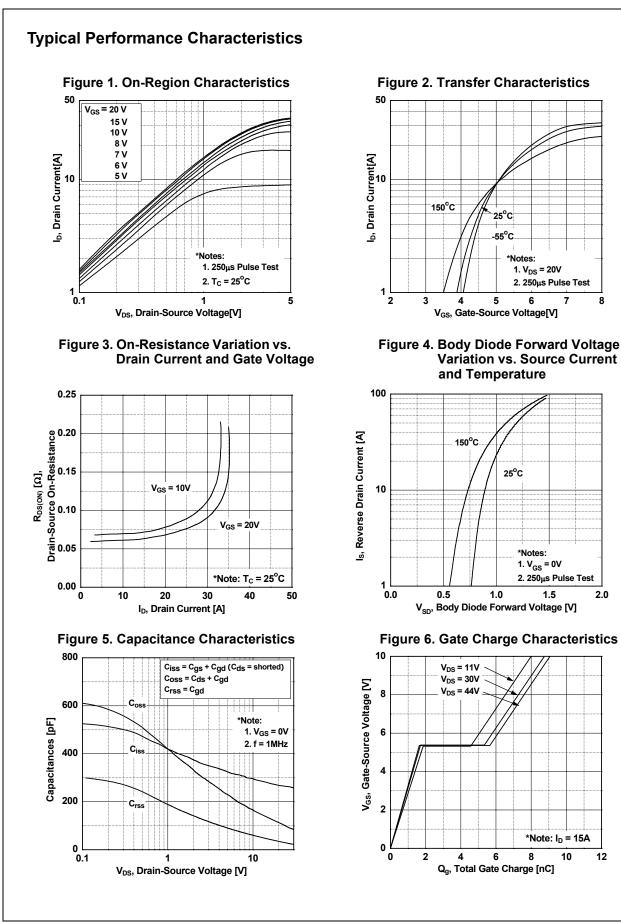
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icient Gate Voltage Drain Curre to Body Leakage Curren	$\frac{V_{DS}}{V_{DS}}$	= 250µA, Referenced t			-	-	V
to Body Leakage Curren	V _D	r = 50V V $r = 0V$	$I_D = 250 \mu A$, Referenced to $25^{\circ}C$		70	-	V/ºC
to Body Leakage Curren	V _D	V _{DS} = 50V, V _{GS} = 0V		-	-	1	
		$V_{\rm DS} = 45V, T_{\rm C} = 150^{\rm o}{\rm C}$			-	250	
cs	ι V _G	$V_{GS} = \pm 20V, V_{DS} = 0V$			-	±100	
Gate Threshold Voltage		V _{GS} = V _{DS} , I _D = 250μA		2.0	-	4.0	V
Static Drain to Source On Resistance		$V_{GS} = 10V, I_D = 15A$		-	0.75	0.90	Ω
Forward Transconductance		V _{DS} = 20V, I _D = 15A			5	-	S
teristics							
				-	265	350	pF
utput Capacitance		— V _{DS} = 25V, V _{GS} = 0V — f = 1MHz		-	97		pF
				-	28		pF
			-	8.8	11.5	nC	
-	V _{DS} = 30V,I _D = 15A		-	-	1.7	-	nC
to Drain "Miller" Charge	V _G				3.6	-	nC
octoristics				I		1	.1
				_	9.5	29	ns
	V	$V_{DD} = 30V, I_D = 15A$		-		-	ns
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R_{BJC} is guaranteed by</td><td>Cteristics - 265 Capacitance $V_{DS} = 25V$, $V_{GS} = 0V$ - 97 rse Transfer Capacitance f = 1MHz - 28 Gate Charge at 10V $V_{DS} = 30V, I_D = 15A$ - 1.7 to Source Gate Charge $V_{DS} = 30V, I_D = 15A$ - 1.7 to Drain "Miller" Charge $V_{DS} = 10V$ (Note 4) - 3.6 acteristics On Delay Time $V_{DD} = 30V, I_D = 15A$ - 97 Off Delay Time $R_G = 25\Omega$ (Note 4) - 22.5 Off Fall Time $V_{CS} = 0V, I_{SD} = 15A$ - - - num Continuous Drain to Source Diode Forward Current - - - - num Pulsed Drain to Source Diode Forward Current - - - - num Pulsed Drain to Source Diode Forward Current - - - - rse Recovery Time $V_{GS} = 0V, I_{SD} = 15A$ - - - rse Recovery Time $V_{GS} = 0V, I_{SD} = 15A$ - 30 - rse Recovery Charge dI_F/dt = 100A/µs <</td><td>Creation of the second second</td></td<>	Capacitance $V_{DS} = 25V, V_{GS} = 0V$ - It Capacitance $f = 1MHz$ - rse Transfer Capacitance $f = 1MHz$ - Gate Charge at 10V $V_{DS} = 30V, I_D = 15A$ - to Drain "Miller" Charge $V_{DS} = 30V, I_D = 15A$ - to Drain "Miller" Charge $V_{DD} = 30V, I_D = 15A$ - On Delay Time $V_{DD} = 30V, I_D = 15A$ - Off Delay Time $V_{DD} = 30V, I_D = 15A$ - Off Fall Time $V_{OS} = 0V, I_D = 15A$ - Ode Characteristics - - num Continuous Drain to Source Diode Forward Current - num Pulsed Drain to Source Diode Forward Current - to Source Diode Forward Voltage $V_{GS} = 0V, I_{SD} = 15A$ - trese Recovery Time $V_{GS} = 0V, I_{SD} = 15A$ - trese Recovery Charge $dI_F/dt = 100A/\mu s$ (Note 5) - the device mounted on a 1 in ² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. 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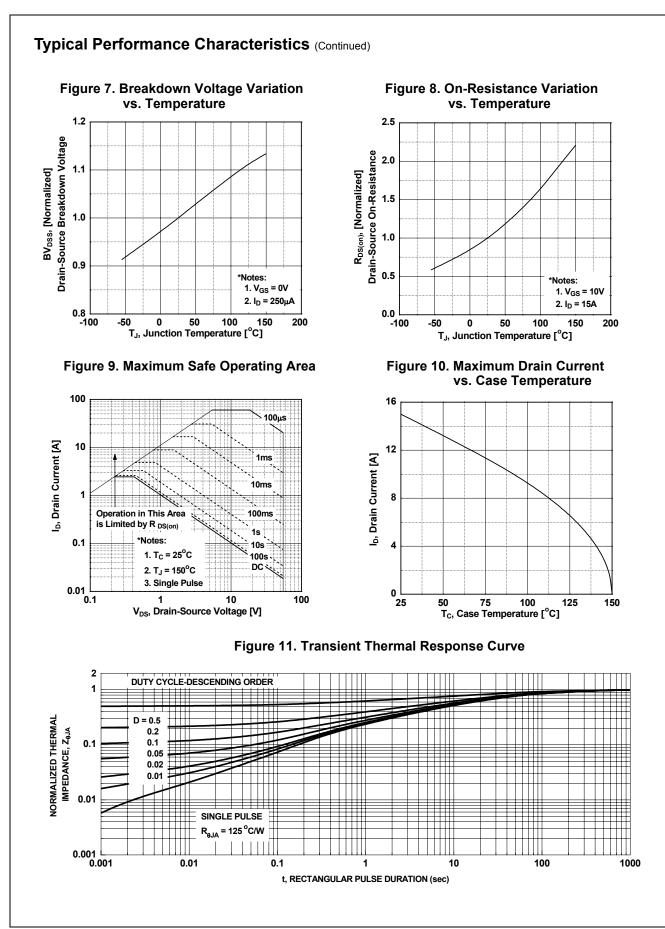
2: Repetitive Rating: Pulse width limited by maximum junction temperature 3: L = 1mH, I_{AS} = 8.5A, R_G = 25\Omega, Starting T_J = 25^{\circ}C

4: Essentially Independent of Operating Temperature Typical Characteristics

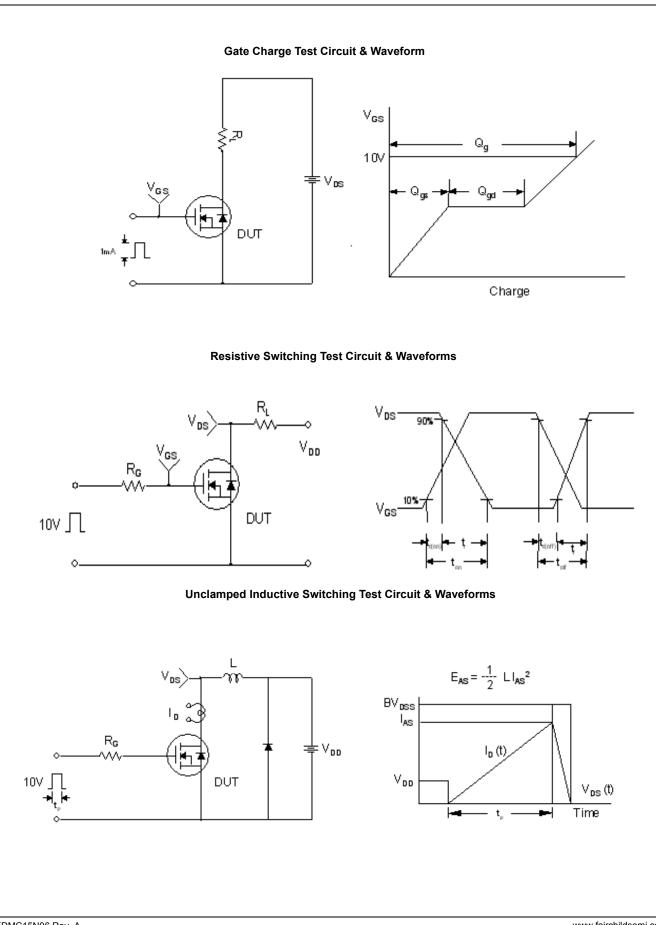
5: I_{SD} \leq 15A, di/dt \leq 200A/µs, V_{DD} \leq 40V, Starting T_J = 25°C

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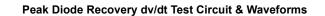


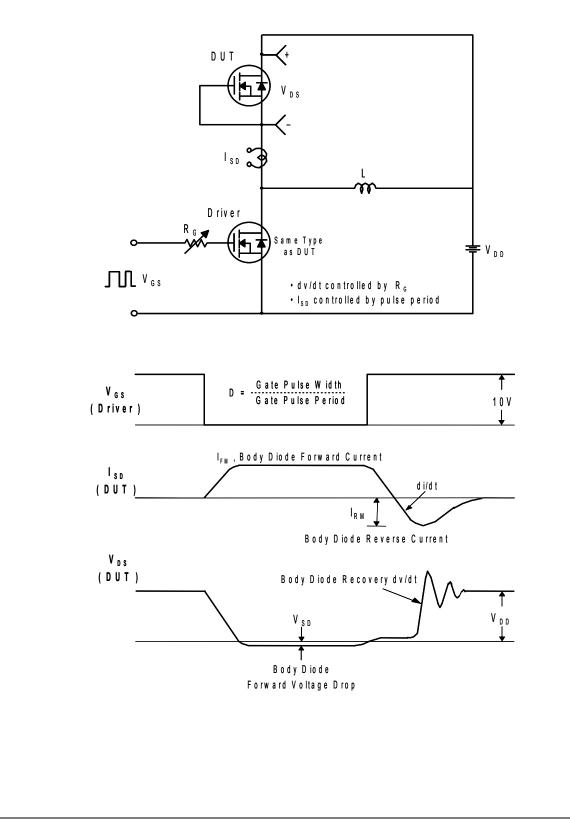


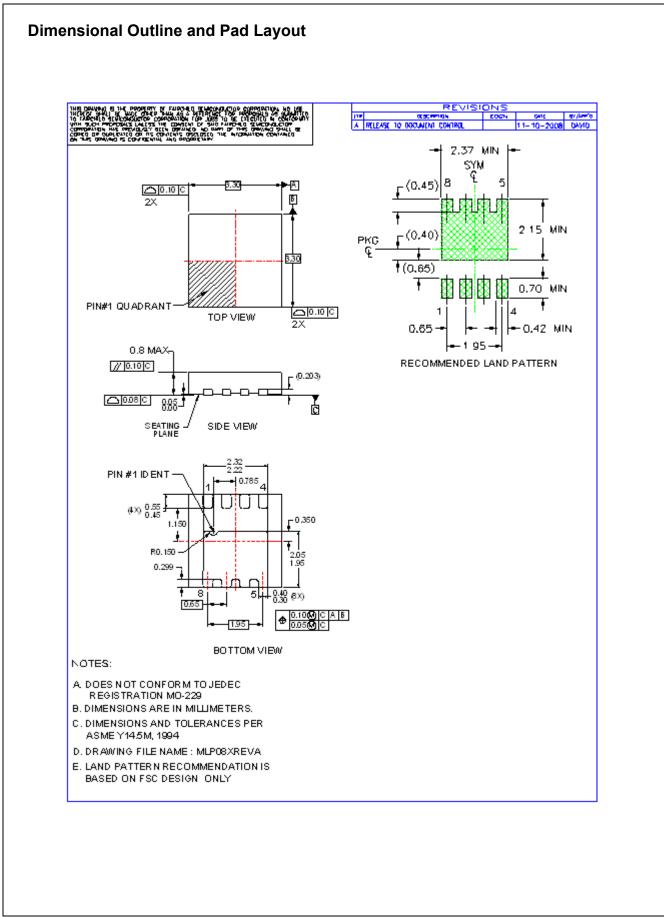
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